

# BGB741L7ESD

**Internally matched general purpose LNA MMIC for 50 MHz- 3.5 GHz applications**



Order now



Technical  
documents



Simulation



Support

## Product description

The BGB741L7ESD is a high performance broadband low noise amplifier (LNA) MMIC based on Infineon's silicon germanium carbon (SiGe:C) bipolar technology.



## Feature list

- Minimum noise figure  $NF_{min} = 1.05 \text{ dB}$  at 2.4 GHz, 3 V, 10 mA
- Supply voltage range  $V_{CC} = 1.8 \text{ to } 4.0 \text{ V}$  at  $T_A = 25^\circ\text{C}$
- High RF input power robustness of 20 dBm
- Integrated ESD protection: 2 kV HBM at all pins

## Product validation

Qualified for industrial applications according to the relevant tests of JEDEC47/20/22.

## Potential applications

- Satellite navigation systems (e.g. GPS, GLONASS, BeiDou, Galileo)
- Wireless communications: WLAN 2.4 GHz and 5-6 GHz bands, broadband LTE or WiMAX LNA
- ISM applications like RKE and smart meter, as well as for emerging wireless applications such as DVB-Terrestrial

## Device information

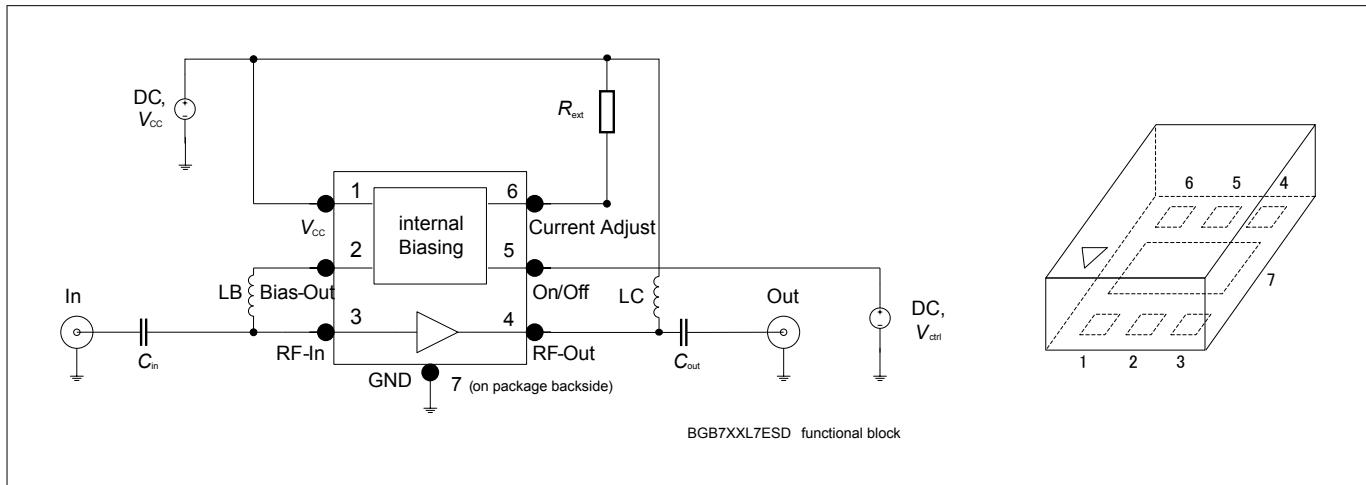
**Table 1 Part information**

Product name / Ordering code	Package	Pin configuration				Marking	Pieces / Reel
BGB741L7ESD / BGB741L7ESDE6327XTSA1	TSLP-7-1	1 = $V_{CC}$	2 = $V_{Bias}$	3 = $RF_{in}$	4 = $RF_{out}$	AY	7500
		5 = $V_{Ctrl}$	6 = Current adjust	7 = Ground			

**Attention: ESD (Electrostatic discharge) sensitive device, observe handling precautions**

**Functional block diagram****Functional block diagram**

This functional block diagram explains how the BGB707L7ESD is used. The RF power on/off function is controlled by applying  $V_{Ctrl}$ . By using an external resistor  $R_{ext}$ , the pre-set current of 5.5 mA (when  $R_{ext}$  is omitted) can be increased. Base  $V_B$  and collector  $V_C$  voltages are applied to the respective pins  $RF_{in}$  and  $RF_{out}$  by external inductors  $L_B$  and  $L_C$ .

**Figure 1**      **Functional block diagram**

**Table of contents****Table of contents**

<b>Product description</b> .....	1
<b>Feature list</b> .....	1
<b>Product validation</b> .....	1
<b>Potential applications</b> .....	1
<b>Device information</b> .....	1
<b>Functional block diagram</b> .....	2
<b>Table of contents</b> .....	3
<b>1 Operating conditions</b> .....	4
<b>2 Absolute maximum ratings</b> .....	5
<b>3 Thermal characteristics</b> .....	6
<b>4 Electrical characteristics</b> .....	7
4.1 DC characteristics .....	7
4.2 Characteristic DC diagrams .....	8
4.3 AC characteristics .....	10
<b>5 Package information TSLP-7-1</b> .....	19
<b>Revision history</b> .....	21
<b>Disclaimer</b> .....	22

**Operating conditions****1 Operating conditions****Table 2 Operation conditions at  $T_A = 25^\circ\text{C}$** 

Parameter	Symbol	Values			Unit	Note or test condition
		Min.	Typ.	Max.		
Supply voltage	$V_{CC}$	1.8	3	4	V	-
Control voltage in on-mode	$V_{Ctrl-on}$	1.2	-	$V_{CC}$		
Control voltage in off-mode	$V_{Ctrl-off}$	-0.3		0.3		

**Absolute maximum ratings****2 Absolute maximum ratings****Table 3 Absolute maximum ratings at  $T_A = 25^\circ\text{C}$  (unless otherwise specified)**

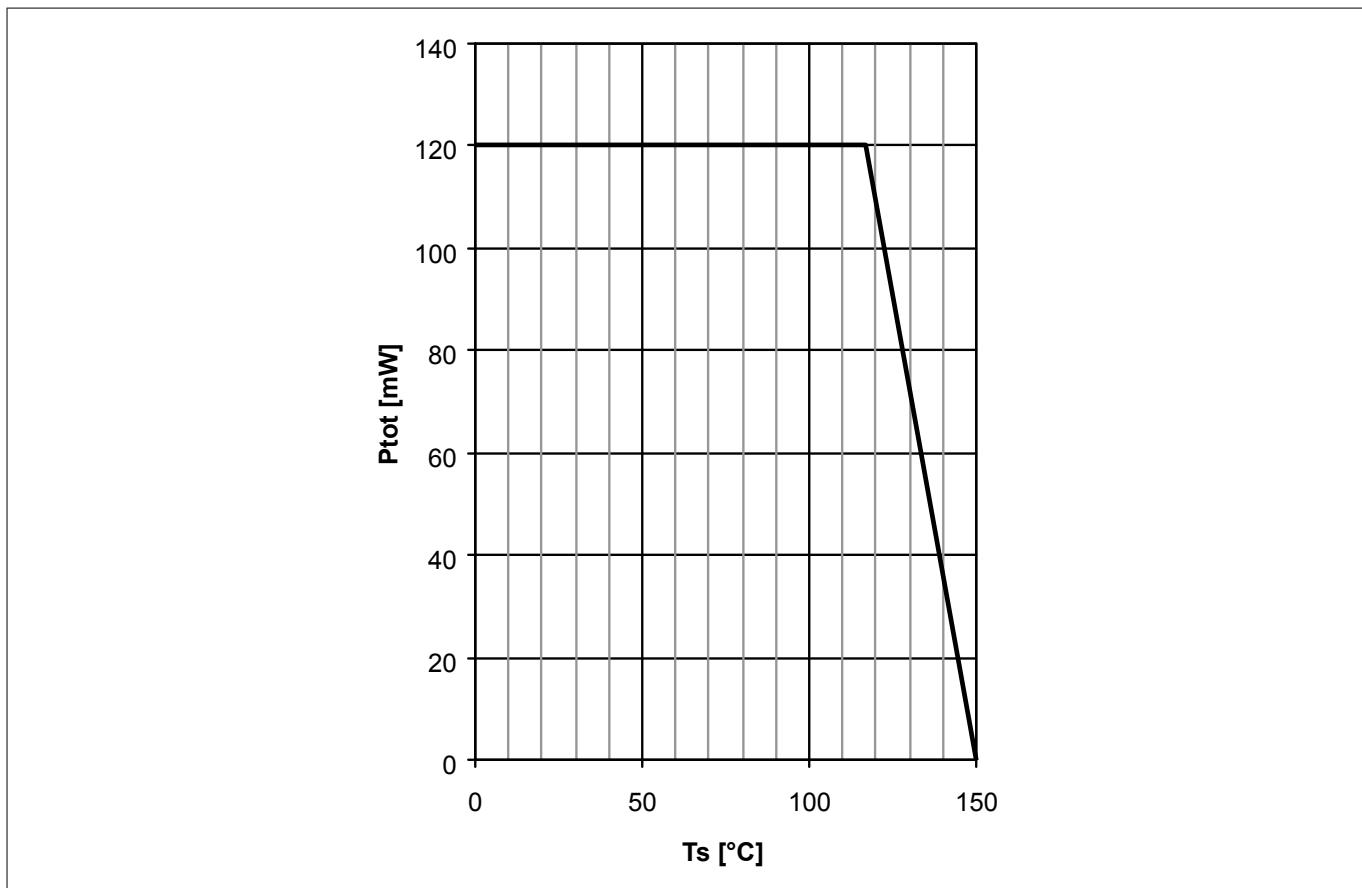
Parameter	Symbol	Values		Unit	Note or test condition
		Min.	Max.		
Supply voltage	$V_{CC}$	-	4 3.5	V	$T_A = 25^\circ\text{C}$ $T_A = -55^\circ\text{C}$
Supply current	$I_{CC}$	30	mA	-	
DC current at $RF_{in}$	$I_B$	3			
Control voltage	$V_{Ctrl}$	$V_{CC}$	V		
ESD stress pulse (HBM)	$V_{ESD}$	+/- 2			
RF input power	$P_{RFin}$	20	dBm		
Total power dissipation <sup>1</sup>	$P_{tot}$	120			
Junction temperature	$T_J$	150	°C	-	
Storage temperature	$T_{Stg}$				

**Attention:** *Stresses above the max. values listed here may cause permanent damage to the device. Exposure to absolute maximum rating conditions for extended periods may affect device reliability. Exceeding only one of these values may cause irreversible damage to the integrated circuit.*

<sup>1</sup>  $T_S$  is the soldering point temperature.  $T_S$  is measured on the emitter lead at the soldering point of the PCB

**Thermal characteristics****3 Thermal characteristics****Table 4 Thermal resistance**

Parameter	Symbol	Values			Unit	Note or test condition
		Min.	Typ.	Max.		
Junction - soldering point	$R_{\text{thJS}}$	-	275	-	K/W	-

**Figure 2****Total power dissipation  $P_{\text{tot}} = f(T_s)$**

---

**Electrical characteristics**

## 4 Electrical characteristics

### 4.1 DC characteristics

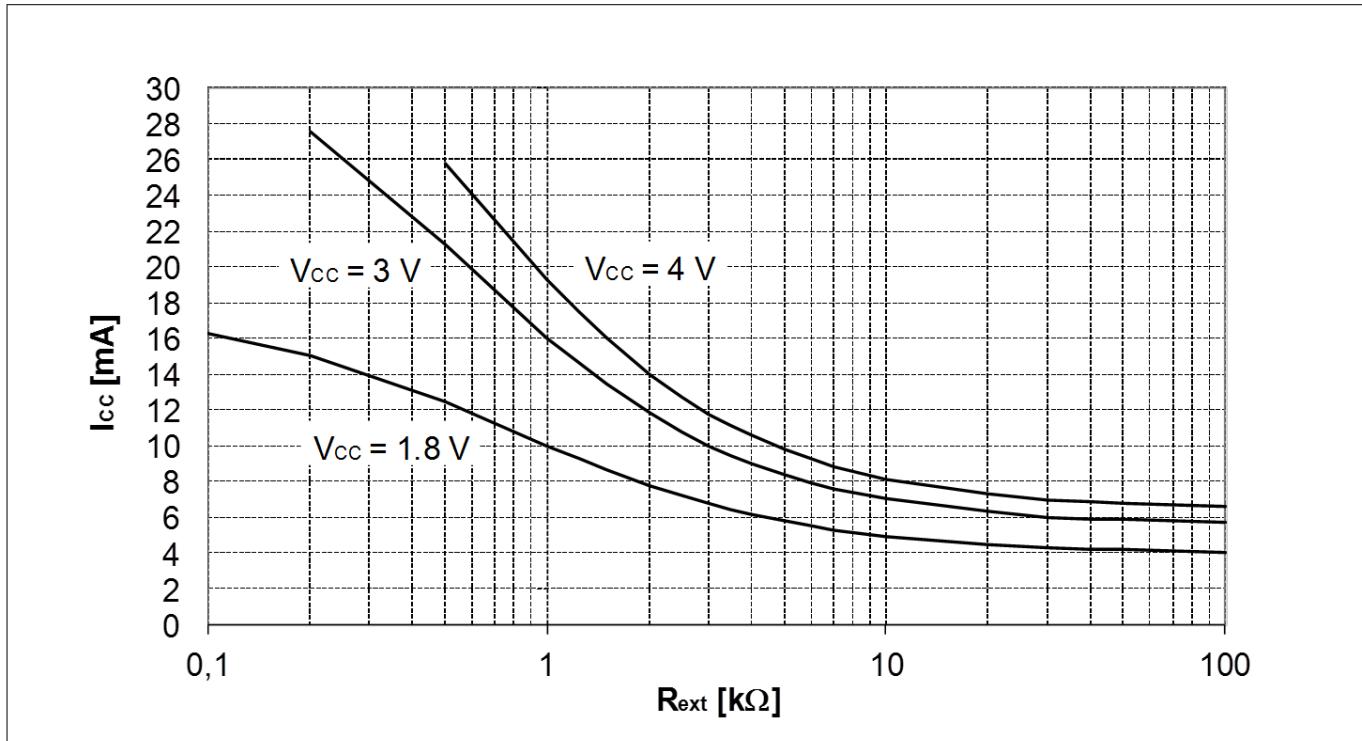
**Table 5 DC characteristics at  $V_{CC} = 3\text{ V}$ ,  $T_A = 25\text{ }^\circ\text{C}$**

Parameter	Symbol	Values			Unit	Note or test condition
		Min.	Typ.	Max.		
Supply current in on-mode	$I_{CC\text{-on}}$	5.0	5.5	6.5	mA	$V_{Ctrl} = 3\text{ V}$
		-	6	-		$R_{ext} = \text{open}$
		-	10	-		$R_{ext} = 30\text{ k}\Omega$
Supply current in off-mode	$I_{CC\text{-off}}$	-	-	6	$\mu\text{A}$	$R_{ext} = 3\text{ k}\Omega$
Control current in on-mode	$I_{Ctrl\text{-on}}$		14	20		$V_{Ctrl} = 0\text{ V}$
Control current in off-mode	$I_{Ctrl\text{-off}}$		-	0.1		$V_{Ctrl} = 3\text{ V}$

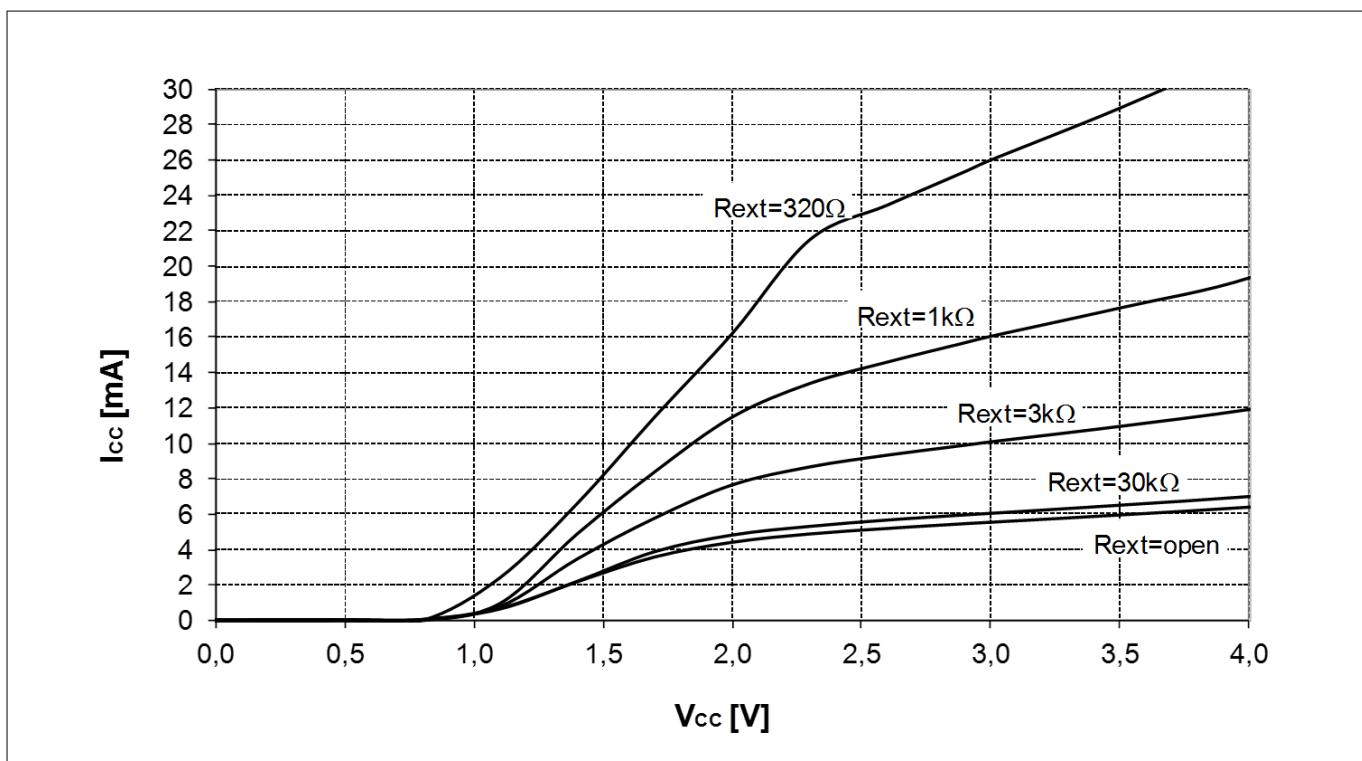
## Electrical characteristics

### 4.2 Characteristic DC diagrams

The measurement setup is an application circuit according to [Figure 1](#) on page 2, using the integrated biasing.  $T_A = 25^\circ\text{C}$  (unless otherwise specified).

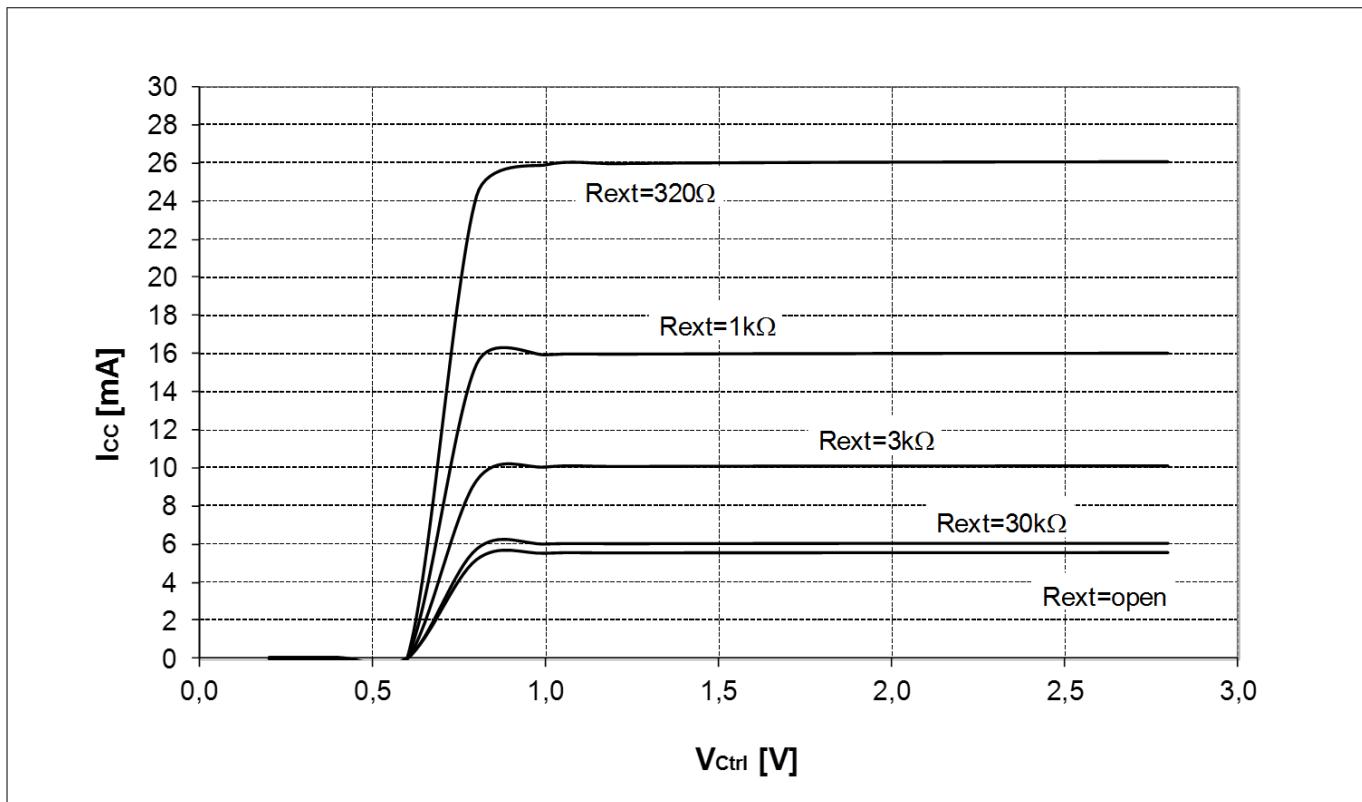
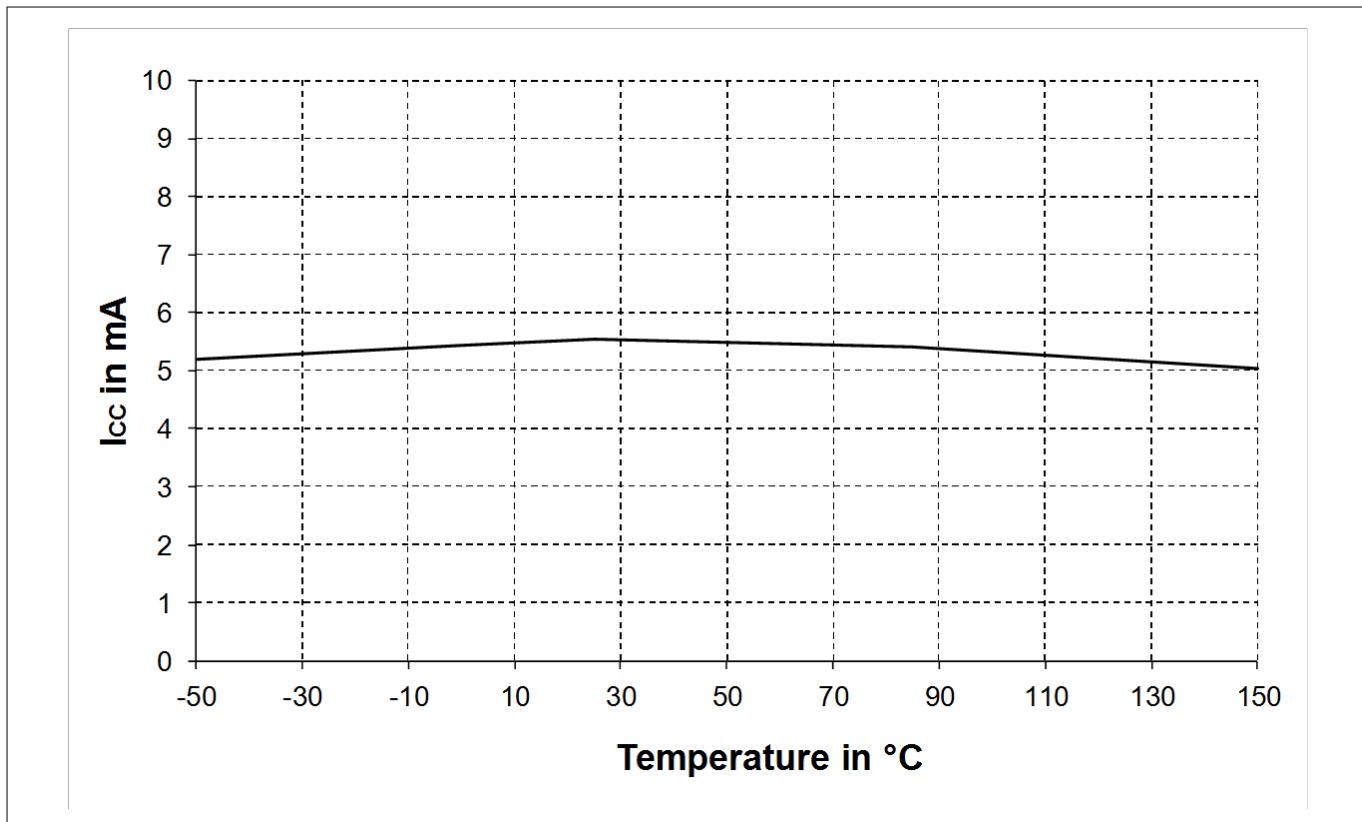


**Figure 3** Supply current vs external resistance  $I_{\text{cc}} = f(R_{\text{ext}})$ ,  $V_{\text{ctrl}} = 3 \text{ V}$ ,  $V_{\text{cc}}$  = parameter



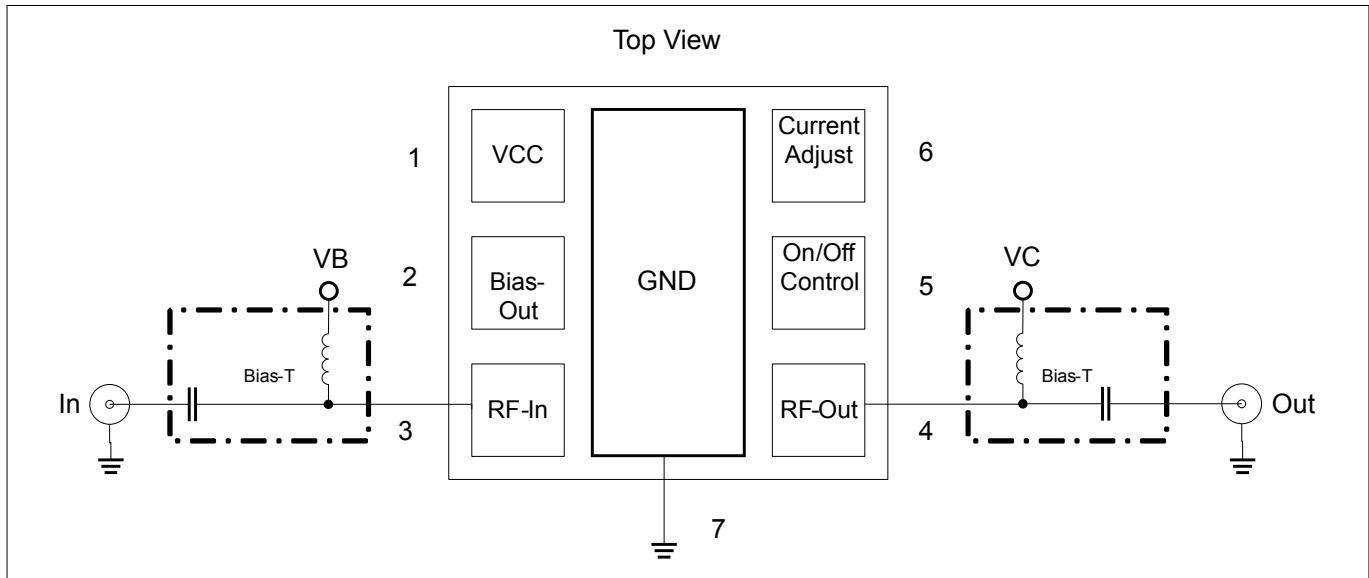
**Figure 4** Supply current vs supply voltage  $I_{\text{cc}} = f(V_{\text{cc}})$ ,  $V_{\text{ctrl}} = 3 \text{ V}$ ,  $R_{\text{ext}}$  = parameter

## Electrical characteristics

Figure 5 Supply current vs control voltage  $I_{CC} = f(V_{Ctrl})$ ,  $V_{CC} = 3$  V,  $R_{ext}$  = parameterFigure 6 Supply current vs temperature  $I_{CC} = f(T_A)$ ,  $V_{ctrl} = V_{CC} = 3$  V,  $R_{ext}$  = open

**Electrical characteristics****4.3 AC characteristics**

The measurement setup is a test fixture with Bias-T's in a 50 Ω system,  $T_A = 25^\circ\text{C}$ .

**Figure 7****Testing setup**

## Electrical characteristics

**Table 6** AC characteristics,  $V_C = 3$  V,  $f = 150$  MHz

Parameter	Symbol	Values			Unit	Note or test condition
		Min.	Typ.	Max.		
Minimum noise figure <sup>1)</sup>	$NF_{min}$	-	1.05	-	dB	$I_C = 6$ mA
			0.95			$I_C = 10$ mA $Z_S = Z_{S,opt}$
Noise figure in 50 $\Omega$ system <sup>2)</sup>	$NF_{50}$		1.1			$I_C = 6$ mA
			1.05			$I_C = 10$ mA $Z_S = Z_L = 50 \Omega$
Transducer gain	$ S_{21} ^2$		19			$I_C = 6$ mA
			21			$I_C = 10$ mA
Maximum stable power gain	$G_{ms}$		20			$I_C = 6$ mA
			21.5			$I_C = 10$ mA
Input 1 dB gain compression point	$IP_{1dB}$		-5.5		dBm	$I_{Cq} = 6$ mA
			-8			$I_{Cq} = 10$ mA
Input 3 <sup>rd</sup> order intercept point	$IIP_3$		5.5			$I_C = 6$ mA
			3.5			$I_C = 10$ mA
Input return loss	$RL_{in}$		14		dB	$I_C = 6$ mA
			18			$I_C = 10$ mA
Output return loss	$RL_{out}$		12.5			$I_C = 6$ mA
			18.5			$I_C = 10$ mA

<sup>1</sup> Test fixture losses are extracted<sup>2</sup> Parameter measured on an application board according to **Figure 1** on page 2 presenting a 50  $\Omega$  system to the device.  $I_{Cq}$  is the quiescent current, that is at small RF input power level.  $I_C$  increases as RF input power level approaches  $IP_{1dB}$ .

## Electrical characteristics

Table 7 AC characteristics,  $V_C = 3$  V,  $f = 450$  MHz

Parameter	Symbol	Values			Unit	Note or test condition
		Min.	Typ.	Max.		
Minimum noise figure <sup>1)</sup>	$NF_{min}$	-	1.05	-	dB	$I_C = 6$ mA
			0.95			$I_C = 10$ mA
			1.1			$Z_S = Z_{S,opt}$
Noise figure in 50 $\Omega$ system <sup>2)</sup>	$NF_{50}$		1.05			$I_C = 6$ mA
			1.1			$I_C = 10$ mA
Transducer gain	$ S_{21} ^2$		18.5			$Z_S = Z_L = 50 \Omega$
			20.5			$I_C = 6$ mA
Maximum available power gain	$G_{ma}$		19			$I_C = 10$ mA
			20.5			$I_C = 6$ mA
Input 1 dB gain compression point	$IP_{1dB}$		-5		dBm	$I_{Cq} = 6$ mA
			-7.5			$I_{Cq} = 10$ mA
Input 3 <sup>rd</sup> order intercept point			4			$I_C = 6$ mA
			2.5			$I_C = 10$ mA
Input return loss	$RL_{in}$		15.5		dB	$I_C = 6$ mA
			21			$I_C = 10$ mA
Output return loss	$RL_{out}$		14.5			$I_C = 6$ mA
			28			$I_C = 10$ mA

<sup>1</sup> Test fixture losses are extracted<sup>2</sup> Parameter measured on an application board according to **Figure 1** on page 2 presenting a 50  $\Omega$  system to the device.  $I_{Cq}$  is the quiescent current, that is at small RF input power level.  $I_C$  increases as RF input power level approaches  $IP_{1dB}$ .

## Electrical characteristics

**Table 8** AC characteristics,  $V_C = 3$  V,  $f = 900$  MHz

Parameter	Symbol	Values			Unit	Note or test condition
		Min.	Typ.	Max.		
Minimum noise figure <sup>1)</sup>	$NF_{min}$	-	1.05	-	dB	$I_C = 6$ mA
			0.95			$I_C = 10$ mA
			1.1			$Z_S = Z_{S,opt}$
Noise figure in 50 $\Omega$ system <sup>2)</sup>	$NF_{50}$		1.05			$I_C = 6$ mA
			1.1			$I_C = 10$ mA
Transducer gain	$ S_{21} ^2$		18.5			$Z_S = Z_L = 50 \Omega$
			20			
Maximum available power gain	$G_{ma}$		19			$I_C = 6$ mA
			20.5			$I_C = 10$ mA
Input 1 dB gain compression point	$IP_{1dB}$		-5		dBm	$I_{Cq} = 6$ mA
			-7			$I_{Cq} = 10$ mA
			3			$I_C = 6$ mA
			1.5			$I_C = 10$ mA
Input return loss	$RL_{in}$		15.5		dB	$I_C = 6$ mA
			19			$I_C = 10$ mA
Output return loss	$RL_{out}$		14.5			$I_C = 6$ mA
			28.5			$I_C = 10$ mA

<sup>1</sup> Test fixture losses are extracted<sup>2</sup> Parameter measured on an application board according to **Figure 1** on page 2 presenting a 50  $\Omega$  system to the device.  $I_{Cq}$  is the quiescent current, that is at small RF input power level.  $I_C$  increases as RF input power level approaches  $IP_{1dB}$ .

## Electrical characteristics

**Table 9** AC characteristics,  $V_C = 3$  V,  $f = 1.5$  GHz

Parameter	Symbol	Values			Unit	Note or test condition
		Min.	Typ.	Max.		
Minimum noise figure <sup>1)</sup>	$NF_{min}$	-	1.05	-	dB	$I_C = 6$ mA
			1.0			$I_C = 10$ mA $Z_S = Z_{S,opt}$
Noise figure in 50 $\Omega$ system <sup>2)</sup>	$NF_{50}$		1.1			$I_C = 6$ mA
			1.05			$I_C = 10$ mA $Z_S = Z_L = 50 \Omega$
Transducer gain	$ S_{21} ^2$		18			$I_C = 6$ mA
			19.5			$I_C = 10$ mA
Maximum available power gain	$G_{ma}$		18.5			$I_C = 6$ mA
			20			$I_C = 10$ mA
Input 1 dB gain compression point	$IP_{1dB}$		-4.5		dBm	$I_{Cq} = 6$ mA
			-6.5			$I_{Cq} = 10$ mA
Input 3 <sup>rd</sup> order intercept point	$IIP_3$		2.5			$I_C = 6$ mA
			1			$I_C = 10$ mA
Input return loss	$RL_{in}$		14.5		dB	$I_C = 6$ mA
			16			$I_C = 10$ mA
Output return loss	$RL_{out}$		14			$I_C = 6$ mA
			23			$I_C = 10$ mA

<sup>1</sup> Test fixture losses are extracted<sup>2</sup> Parameter measured on an application board according to **Figure 1** on page 2 presenting a 50  $\Omega$  system to the device.  $I_{Cq}$  is the quiescent current, that is at small RF input power level.  $I_C$  increases as RF input power level approaches  $IP_{1dB}$ .

## Electrical characteristics

**Table 10** AC characteristics,  $V_C = 3$  V,  $f = 1.9$  GHz

Parameter	Symbol	Values			Unit	Note or test condition
		Min.	Typ.	Max.		
Minimum noise figure <sup>1)</sup>	$NF_{min}$	-	1.05	-	dB	$I_C = 6$ mA $I_C = 10$ mA $Z_S = Z_{S,opt}$
Noise figure in 50 $\Omega$ system <sup>2)</sup>			1.15	1.1		$I_C = 6$ mA $I_C = 10$ mA $Z_S = Z_L = 50 \Omega$
Transducer gain	$ S_{21} ^2$	17.5 19	18	19.5	dBm	$I_C = 6$ mA $I_C = 10$ mA
Maximum available power gain			-4	-6		$I_{Cq} = 6$ mA $I_{Cq} = 10$ mA
Input 1 dB gain compression point	$IP_{1dB}$	2.5 1	13.5	15	dB	$I_C = 6$ mA $I_C = 10$ mA
Input 3 <sup>rd</sup> order intercept point			13.5	21		$I_C = 6$ mA $I_C = 10$ mA
Input return loss	$RL_{in}$	13.5 15	13.5	15	dB	$I_C = 6$ mA $I_C = 10$ mA
Output return loss			13.5	21		$I_C = 6$ mA $I_C = 10$ mA

<sup>1</sup> Test fixture losses are extracted<sup>2</sup> Parameter measured on an application board according to **Figure 1** on page 2 presenting a 50  $\Omega$  system to the device.  $I_{Cq}$  is the quiescent current, that is at small RF input power level.  $I_C$  increases as RF input power level approaches  $IP_{1dB}$ .

## Electrical characteristics

**Table 11** AC characteristics,  $V_C = 3$  V,  $f = 2.4$  GHz

Parameter	Symbol	Values			Unit	Note or test condition
		Min.	Typ.	Max.		
Minimum noise figure <sup>1)</sup>	$NF_{min}$	-	1.1	-	dB	$I_C = 6$ mA
			1.05			$I_C = 10$ mA $Z_S = Z_{S,opt}$
Noise figure in 50 $\Omega$ system <sup>2)</sup>	$NF_{50}$		1.15			$I_C = 6$ mA
			1.1			$I_C = 10$ mA $Z_S = Z_L = 50 \Omega$
Transducer gain	$ S_{21} ^2$		17			$I_C = 6$ mA
			18.5			$I_C = 10$ mA
Maximum available power gain	$G_{ma}$		17.5			$I_C = 6$ mA
			19			$I_C = 10$ mA
Input 1 dB gain compression point	$IP_{1dB}$		-3.5		dBm	$I_{Cq} = 6$ mA
			-5.5			$I_{Cq} = 10$ mA
Input 3 <sup>rd</sup> order intercept point	$IIP_3$		3			$I_C = 6$ mA
			1			$I_C = 10$ mA
Input return loss	$RL_{in}$		12.5		dB	$I_C = 6$ mA
			13.5			$I_C = 10$ mA
Output return loss	$RL_{out}$		12.5			$I_C = 6$ mA
			18			$I_C = 10$ mA

<sup>1</sup> Test fixture losses are extracted<sup>2</sup> Parameter measured on an application board according to **Figure 1** on page 2 presenting a 50  $\Omega$  system to the device.  $I_{Cq}$  is the quiescent current, that is at small RF input power level.  $I_C$  increases as RF input power level approaches  $IP_{1dB}$ .

## Electrical characteristics

**Table 12** AC characteristics,  $V_C = 3$  V,  $f = 3.5$  GHz

Parameter	Symbol	Values			Unit	Note or test condition
		Min.	Typ.	Max.		
Minimum noise figure <sup>1)</sup>	$NF_{min}$	-	1.25	-	dB	$I_C = 6$ mA
			1.2			$I_C = 10$ mA $Z_S = Z_{S,opt}$
Noise figure in 50 $\Omega$ system <sup>2)</sup>	$NF_{50}$		1.35			$I_C = 6$ mA
			1.25			$I_C = 10$ mA $Z_S = Z_L = 50 \Omega$
Transducer gain	$ S_{21} ^2$		15			$I_C = 6$ mA
			16.5			$I_C = 10$ mA
Maximum available power gain	$G_{ma}$		16			$I_C = 6$ mA
			17.5			$I_C = 10$ mA
Input 1 dB gain compression point	$IP_{1dB}$		-2.5		dBm	$I_{Cq} = 6$ mA
			-4.5			$I_{Cq} = 10$ mA
Input 3 <sup>rd</sup> order intercept point	$IIP_3$		3.5			$I_C = 6$ mA
			1.5			$I_C = 10$ mA
Input return loss	$RL_{in}$		10		dB	$I_C = 6$ mA
			10.5			$I_C = 10$ mA
Output return loss	$RL_{out}$		10			$I_C = 6$ mA
			13.5			$I_C = 10$ mA

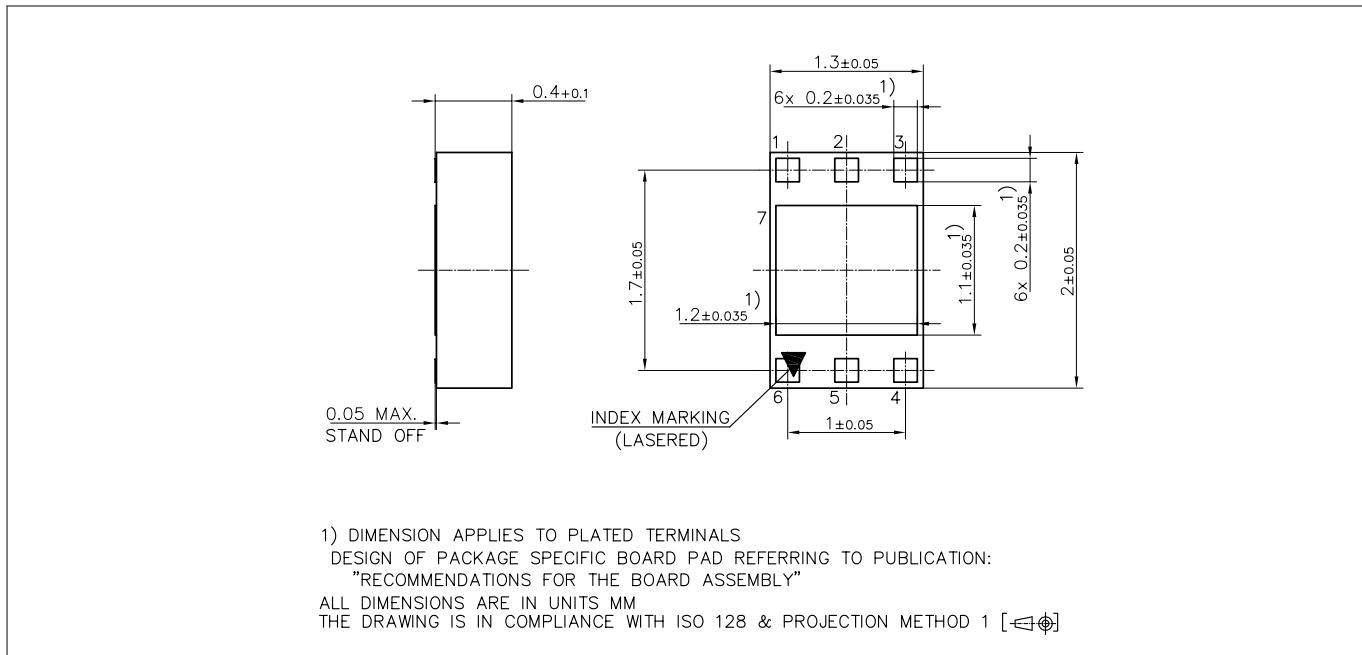
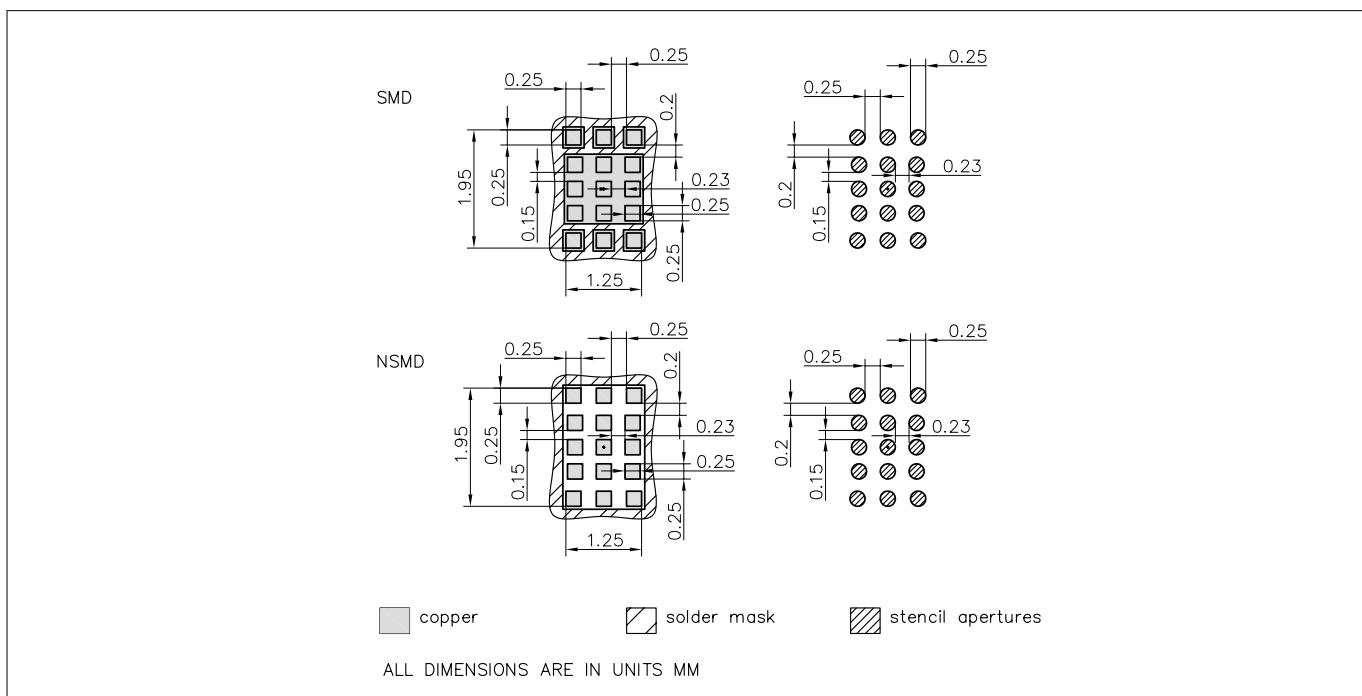
<sup>1</sup> Test fixture losses are extracted<sup>2</sup> Parameter measured on an application board according to **Figure 1** on page 2 presenting a 50  $\Omega$  system to the device.  $I_{Cq}$  is the quiescent current, that is at small RF input power level.  $I_C$  increases as RF input power level approaches  $IP_{1dB}$ .

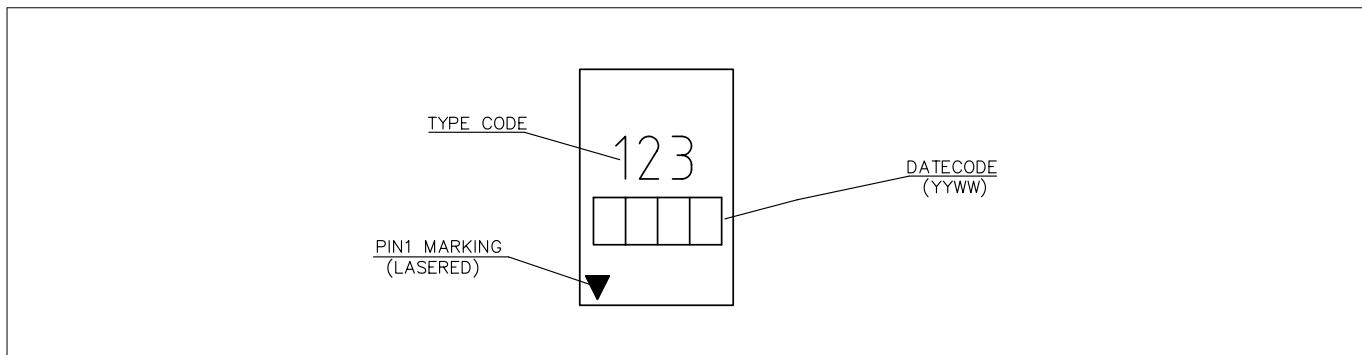
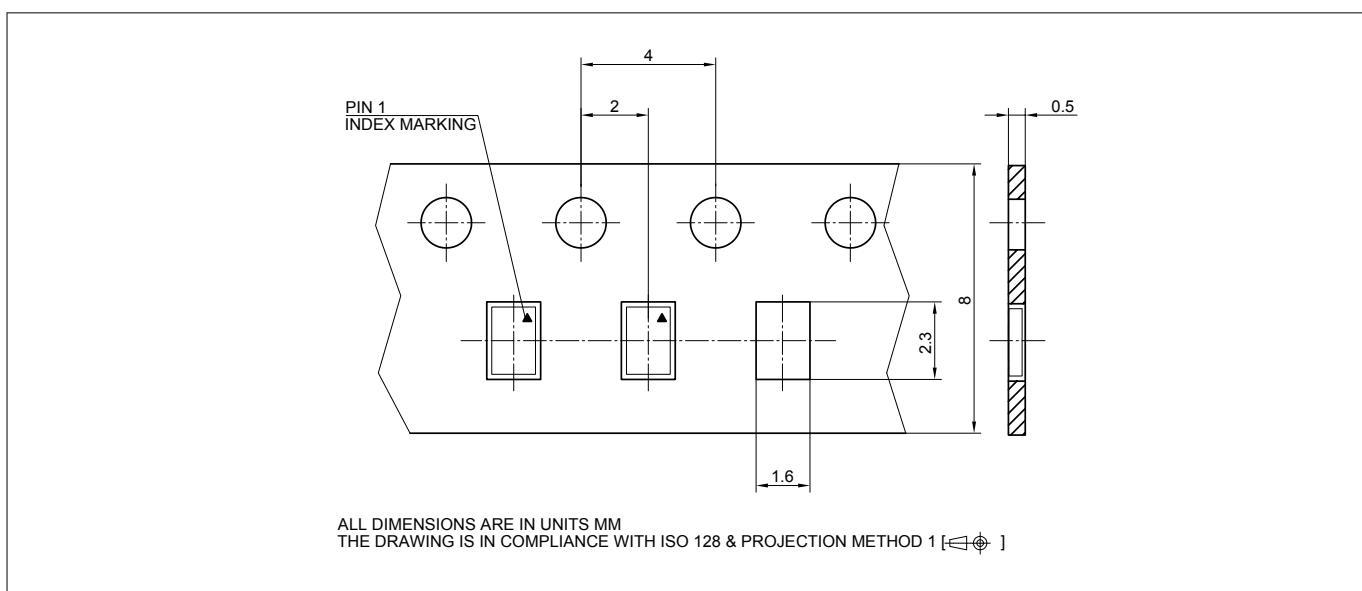
## Electrical characteristics

**Table 13** AC characteristics,  $V_C = 3$  V,  $f = 5.5$  GHz

Parameter	Symbol	Values			Unit	Note or test condition
		Min.	Typ.	Max.		
Minimum noise figure <sup>1)</sup>	$NF_{min}$	-	1.8	-	dB	$I_C = 6$ mA
			1.75			$I_C = 10$ mA $Z_S = Z_{S,opt}$
Noise figure in 50 $\Omega$ system <sup>2)</sup>	$NF_{50}$		1.95			$I_C = 6$ mA
			1.85			$I_C = 10$ mA $Z_S = Z_L = 50 \Omega$
Transducer gain	$ S_{21} ^2$		12			$I_C = 6$ mA
			13			$I_C = 10$ mA
Maximum available power gain	$G_{ma}$		14			$I_C = 6$ mA
			15			$I_C = 10$ mA
Input 1 dB gain compression point	$IP_{1dB}$		-1		dBm	$I_{Cq} = 6$ mA
			-3			$I_{Cq} = 10$ mA
Input 3 <sup>rd</sup> order intercept point	$IIP_3$		8.5			$I_C = 6$ mA
			4			$I_C = 10$ mA
Input return loss	$RL_{in}$		7		dB	$I_C = 6$ mA
			8			$I_C = 10$ mA
Output return loss	$RL_{out}$		7			$I_C = 6$ mA
			8.5			$I_C = 10$ mA

<sup>1</sup> Test fixture losses are extracted<sup>2</sup> Parameter measured on an application board according to **Figure 1** on page 2 presenting a 50  $\Omega$  system to the device.  $I_{Cq}$  is the quiescent current, that is at small RF input power level.  $I_C$  increases as RF input power level approaches  $IP_{1dB}$ .

**Package information TSLP-7-1****5 Package information TSLP-7-1****Figure 8 Package outline****Figure 9 Foot print**

**Package information TSLP-7-1****Figure 10** **Marking layout example****Figure 11** **Tape information**

Note: See our [Recommendations for Printed Circuit Board Assembly of TSLP/TSSLP/TSNP Packages](#).  
The marking layout is an example. For the real marking code refer to the device information on the first page. The number of characters shown in the layout example is not necessarily the real one. The marking layout can consist of less characters.

**Revision history****Revision history**

Document version	Date of release	Description of changes
3.0	2018-09-26	New datasheet layout.

## **Trademarks**

All referenced product or service names and trademarks are the property of their respective owners.

**Edition 2018-09-26**

**Published by**

**Infineon Technologies AG  
81726 Munich, Germany**

**© 2018 Infineon Technologies AG  
All Rights Reserved.**

**Do you have a question about any aspect of this document?**

**Email: [erratum@infineon.com](mailto:erratum@infineon.com)**

**Document reference  
IFX-zev1491985034409**

## **IMPORTANT NOTICE**

The information given in this document shall in no event be regarded as a guarantee of conditions or characteristics ("Beschaffenheitsgarantie").

With respect to any examples, hints or any typical values stated herein and/or any information regarding the application of the product, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation warranties of non-infringement of intellectual property rights of any third party.

In addition, any information given in this document is subject to customer's compliance with its obligations stated in this document and any applicable legal requirements, norms and standards concerning customer's products and any use of the product of Infineon Technologies in customer's applications.

The data contained in this document is exclusively intended for technically trained staff. It is the responsibility of customer's technical departments to evaluate the suitability of the product for the intended application and the completeness of the product information given in this document with respect to such application.

## **WARNINGS**

Due to technical requirements products may contain dangerous substances. For information on the types in question please contact your nearest Infineon Technologies office.

Except as otherwise explicitly approved by Infineon Technologies in a written document signed by authorized representatives of Infineon Technologies, Infineon Technologies' products may not be used in any applications where a failure of the product or any consequences of the use thereof can reasonably be expected to result in personal injury

# X-ON Electronics

Largest Supplier of Electrical and Electronic Components

***Click to view similar products for RF System on a Chip - SoC category:***

***Click to view products by Infineon manufacturer:***

Other Similar products are found below :

[BCM20733A3KFB1G](#) [ATWILC1000-MR110PA](#) [BCM20737A1KML2G](#) [BCM43236BKMLG](#) [EM250-RTR](#) [CY8C4127FNI-BL483T](#)  
[CYBL10463-56LQXI](#) [CYBL10562-56LQXI](#) [CYBL10563-68FLXIT](#) [CYBL11172-56LQXI](#) [ATBTLC1000A-UU-T](#) [BCM43242KFFBG](#)  
[BCM20707UA1KFFB1G](#) [ATWILC1000B-UU-T](#) [BCM4322KFBGH](#) [EM2420-RTR](#) [ETRX3DVK357](#) [nRF9160-SIBA-R7](#) [88W8897PB1-NXVA/AZ](#) [EC25VFA-MINIPCIE](#) [EC25JFA-MINIPCIE](#) [EC25MXGA-MINIPCIE](#) [EC25AFXGA-MINIPCIE](#) [EC25AUXGA-MINIPCIE](#)  
[EC25AUGC-MINIPCIE](#) [EC25AUTFA-MINIPCIE](#) [EP06ELA-512-SGA](#) [EP06ALA-512-SGAD](#) [EM06ALA-512-SGAD](#) [EM12GPA-512-SGAD](#) [UC200TGLAA-N06-MN0AA](#) [EC25EUGA-MINIPCIE](#) [MCIMX281AVM4B](#) [MCIMX6S6AVM08AC](#) [2087-6001-13](#) [CY8C4127LQI-BL453](#) [CY8C4247FNI-BL483T](#) [CY8C4247FNI-BL493T](#) [CYBL10463-56LQXIT](#) [CC2511F32RSR](#) [ATWILC1000-MR110PB](#) [2087-6001-00](#)  
[ATWINC1500-MR210PA](#) [MCIMX6Q6AVT10AC](#) [DS-319-PIN](#) [NRF51822-CDAB-R](#) [XR1015-QH-0G00](#) [EM3585-RT](#) [NCH-RSL10-101Q48-ABG](#) [AX8052F143-3-TX30](#)